

Notice of References Cited	Application/Control No. 10/565,653		Applicant(s)/Patent Under Reexamination KANAYA ET AL.	
	Examiner Keath T. Chen		Art Unit 1709	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,284,048	09-2001	Van Bilsen et al.	118/666
*	B	US-2002/0066412	06-2002	YAO et al.	118/728
*	C	US-6,162,706	12-2000	Dutartre et al.	438/481
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2000355766 A	12-2000	Japan	IKEDA et al.	C23C 16/44, C30B 25/
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	English Translation of JP 2000355766 A
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.